

智慧醫療研究中心
貴重儀器管理辦法

Valuable Equipment Management
Regulations for the
Research Center for Intelligent
Medical Devices

制定部門：智慧醫療研究中心

Established by: Research Center for Intelligent Medical Devices

中華民國 112 年 12 月 06 日 修訂

Amended on November

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著作權人:明志科技大學

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明志科技大學智慧醫療研究中心貴重儀器管理辦法
MCUT Valuable Equipment Management Regulations for the
Research Center for Intelligent Medical Devices

108.04.17 中心會議制訂

Established by the Center Council Meeting on 2019.04.17

109.03.10 中心會議修訂

Amended by the Center Council Meeting on 2020.03.10

112.12.06 中心會議修訂

Amended by the Center Council Meeting on 2023.12.06

第一條 辦法目的

本校智慧醫療研究中心（以下簡稱本中心）為有效發揮貴重儀器之服務及使用效益，提升學術單位之研究合作並延長機台使用壽命，達到自給自足實現資源共享，訂定「智慧醫療研究中心貴重儀器管理辦法」（以下簡稱本辦法）。

Article 1 Objective/Purpose

MCUT Research Center for Intelligent Medical Devices (hereinafter referred to as “the Center”) has established the “Valuable Equipment Management Regulations for the Research Center for Intelligent Medical Devices” (hereinafter referred to as “the Regulations”) for the effective service and efficiency of valuable equipment. It aims to improve the collaborative research between industries and academia, extend the lives of machines, and further achieve self-sufficiency as well as realize resource sharing.

第二條 服務項目

凡符合中心之發展方向，並屬於中心之購買設備，均可接受外界委託檢測檢驗服務之申請，服務依據本中心各貴重儀器可量測之模式訂定。

一、X 光繞射儀 (X-Ray Diffraction Analysis, XRD)

1. 廣角繞射 (Wide Angle X-Ray Diffraction, WAG)
2. 低掠角薄膜繞射 (Grazing Incidence X-ray Diffraction, GIXRD)
3. 高溫模式 (High Temperature Mode, MTC-HIGHTEMP)

二、場發射掃描式電子顯微鏡 (Field-Emission Scanning Electron Microscope, FE-SEM)

1. 微結構觀察 (Secondary Electron Image, SEI)
2. 背向式散射 (Backscattered Electron Image, BEI)
3. 能量分散式光譜儀 (Energy Dispersive Spectroscopy, EDS)
4. 波長分散式光譜儀 (Wavelength Dispersive Spectroscopy, WDS)

三、掃描探針顯微鏡 (Scanning Probe Microscopy, SPM)

1. 表面形貌 (Contact Mode, Tapping Mode)
2. 單點式/全面式力場曲線 (Force Curve)
3. 磁力顯微模式 (MFM Mode)
4. 靜電力顯微模式 (EFM Mode)
5. 表面電位能顯微模式 (SEPM Mode)
6. 壓電響應顯微模式 (PFM Mode)
7. 導電顯微模式 (CAFM Mode)
8. 掃描電容顯微模式 (SCM Mode)

四、螢光/拉曼光譜儀光譜儀 (Raman & PL Spectrometer)

1. 拉曼光譜量測
2. 拉曼光譜 Mapping 分布分析
3. 螢光光譜模式

五、X 射線螢光光譜儀 (X-Ray Fluorescence, XRF)

1. 特徵螢光波長元素定性定量分析

Article 2 Service Item

Services are set up based on the measurable modes for the Center's valuable equipment.

I. X-Ray Diffraction Analysis (XRD)

1. Wide-Angle X-Ray Diffraction (WAG)
2. Grazing Incidence X-Ray Diffraction (GIXRD)

3. High-Temperature Mode (MTC-HIGHTEMP)

II. Field-Emission Scanning Electron Microscope (FE-SEM)

1. Secondary Electron Image (SEI)
2. Backscattered Electron Image (BEI)
3. Energy-Dispersive X-ray Spectroscopy (EDS)
4. Wavelength-Dispersive X-ray Spectroscopy (WDS)

III. Scanning Probe Microscopy (SPM)

1. Surface Topography (Contact Mode, Tapping Mode)
2. Single-Point/Comprehensive Force Curve
3. MFM Mode
4. EFM Mode
5. SEPM Mode
6. PFM Mode
7. CAFM Mode
8. SCM Mode

IV. Raman & PL Spectrometer

1. Raman spectra
2. Raman spectra Mapping
3. Photoluminescence spectra

V. X-Ray Fluorescence

1. Energy/Wavelength-Dispersive X-ray fluorescence

第三條 委託檢測申請流程

預約作業→實驗樣品送測→完成實驗結果→發送繳費通知→繳費→完成收費→領取試驗報告

委託單位須詳細填寫申請表內容，並請公司主管或指導老師簽名。本中心收到申請表後，經過儀器負責人與本中心負責人簽名確認同意並安排樣品檢測事宜，本中心助理依機台可使用時

間，與委託單位聯繫安排量測日期及時間並按申請表委託檢測項目安排樣品檢測。委託單位必須在檢測日期前三天內將樣品送達或當天自行攜帶送檢，當天完成後會發送繳費通知，待收費完成後將會寄送試驗報告。

Article 3 Commission of Testing Application Process

Appointment → Experimental sample testing → Experiment completion results → Issuance of payment notice → Payment → Completion of charging → Receipt of test reports

The client shall fill out the application form in detail and ask for a signature from the officer of the company or the instructor. Where the Center receives an application form, the person responsible for the equipment and the responsible person of the Center shall sign for validation and approval as well as arrange the sample testing. The Center's assistant shall contact the client to schedule a date and time for measurement in accordance with the availability of the machine. In addition, the sample testing shall be arranged pursuant to the commissioned testing items on the application form. The sample must be delivered to the Center within 3 days before the testing date or be brought by the client for testing on the scheduled day. After the test is finished, a payment notice will be issued on the same day, and the test report will be sent once the charging is completed.

第四條 收費標準

本中心提供貴重儀器委託量測樣品之作業，中心收費標準如附表(表號：A0L0030103 & A0L0030203)，分別為學術界與產業界收費標準，如有變更將另行公告在本中心的網頁。委託單位申請樣品分析時，須在 7 天前先以書面方式提出預約申請，並填寫「明志科技大學智慧醫療研究中心樣品試驗申請單」。(表號：A0L0030303)

Article 4 Rate

The Center provides the commissioned sample measurement service with valuable equipment, which is charged at the rate indicated in the attached table (Form A0L0030103 & A0L0030203). Rates vary according to the machine used for the measurement item. Where any change is made, it will be announced individually on the

website of the Center. Where a client applies for sample analysis, an appointment shall be made in written form 7 days before the test, and the “MCUT Research Center for Intelligent Medical Devices Sample Testing Application Form” shall be completed (Form A0L0030303).

第五條 試驗樣品規範

一、X 光繞射儀 (X-ray diffraction analysis, XRD)

1. 塊材樣品尺寸不得超過:直徑 40mm x 高 4.5mm，粉末樣品裝填載台體積:直徑 25mm x 高 1mm。
2. 不接受具揮發性與毒性之試樣。
3. 高溫模式塊材樣品尺寸不得超過:長 20mm x 寬 10mm x 高 1mm；粉末樣品需備足 0.5 公克以上，不接受具揮發性如有機物、高分子等，低熔點材料如:銦,錫等,會產生相變及蒸鍍效應。

二、場發射掃描式電子顯微鏡 (Field-Emission Scanning Electron Microscope, FE-SEM)

1. 樣品尺寸不得超過：直徑 100 mm x 高 40mm。
2. 為減少儀器不必要的污染，本儀器設備不接受以下材料
 - A. 磁性材料(鐵、鈷、鎳等磁性材料)或易被電磁透鏡吸引的粉末型式樣品。
 - B. 低熔點材料如:銦,錫等,會產生相變及蒸鍍效應。
 - C. 在電子束照射下會分解或釋出氣體之揮發性樣品，如有機物、高分子等，會影響真空、造成污染。
3. 樣品若為粉末材料，可壓製成錠(塊)狀，並確認沒有鬆動粉體。
4. 樣品送驗前先確認已充分乾燥。

三、掃描探針顯微鏡 (Scanning probe microscopy, SPM)

1. 樣品尺寸不得超過：直徑 15mm x 高 20mm。
2. 本儀器設備不接受高粗糙度 $Ra > 2\mu m$ 、具有黏稠度樣品。
3. 樣品若為粉末材料，可壓製成錠(塊)狀，並確認沒有鬆

動粉體。

4. 樣品送驗前先確認已充分乾燥。

四、拉曼光譜儀 (Raman & PL spectroscopy)

1. 樣品尺寸不得超過：直徑 100 mm x 高 10mm。
2. 儀器設備不接受高粗糙度 $Ra > 2\mu\text{m}$ ，或不平整之樣品。

五、X 射線螢光光譜儀 (X-ray fluorescence)

- I. 塊材樣品請準備成尺寸：接近直徑 2 inch 的圓形樣品，高度需低於 30mm。
- II. 粉末樣品需備足可鋪滿直徑 2 inch 圓面積的量。
- III. 液態樣品需備足 20 mL 的量。

六、其餘儀器試樣規範請洽詢中心技士

Article 5 Test Sample Requirements

I. X-Ray Diffraction Analysis (XRD)

1. The size of the bulk material shall not exceed 40 mm (diameter) x 4.5 mm (height); The size of the powder sample filling platform shall be 25 mm (diameter) x 1 mm (height).
2. Testing for volatile and toxic samples will not be provided.
3. The size of the bulk material for the high-temperature mode shall not exceed 20 mm (length) x 10 mm (width) x 1 mm (height). Over 0.5 g of a powder sample shall be prepared. In addition, volatile (e.g., organics and macromolecules) and low melting point materials (e.g., indium and tin) will not be accepted lest phase transition and evaporation deposition occur.

II. Field-Emission Scanning Electron Microscope (FE-SEM)

1. The sample size shall not exceed 100 mm (diameter) x 40 mm (height).
2. To avoid unnecessary contamination, the following materials will not be accepted for this equipment:
 - i. Magnetic materials (e.g., iron, cobalt, and nickel) or powdered samples that are easily attracted by electromagnetic lenses;
 - ii. Low melting point materials (e.g., indium and tin), which incur phase transition and evaporation deposition;

iii. Volatile samples that decompose or release gas under exposure to electron beams, such as organics and macromolecules. These will affect the vacuum status and cause contamination.

3. Where the sample is a powdered material, it may be compressed into a tablet-shaped (bulk) material. Whether the powder is adequately compacted shall be confirmed.
4. Whether the sample is completely dry shall be confirmed before it is sent for testing.

III. Scanning Probe Microscopy (SPM)

1. The sample size shall not exceed 15 mm (diameter) x 20 mm (height).
2. Samples with high roughness (Ra) greater than 2 μm or viscosity will not be accepted for this equipment.
3. Where the sample is a powdered material, it may be compressed into a tablet-shaped (bulk) material. Whether the powder is adequately compacted shall be confirmed.
4. Whether the sample is completely dry shall be confirmed before it is sent for testing.

IV. Raman & PL spectroscopy

1. The sample size shall not exceed 100 mm (diameter) x 10 mm (height).
2. Samples with high roughness (Ra) greater than 2 μm

V. X-Ray Fluorescence

1. Bulk samples, please prepare specimens with dimensions close to a circular shape with a diameter of 2 inches and a height below 30mm.
2. Powder samples, ensure an ample quantity that can cover the entire circular area with a diameter of 2 inches.
3. Liquid samples should be prepared in a volume exceeding 20 mL.

VI. Test sample requirements for other instruments can be obtained by contacting the center technicians

第六條 受託試驗經費運用

- 一、 委託檢測服務費用總金額之百分之二十為學校管理費，百

分之八十為本中心之材料費、人事費、教育訓練費、耗材費，文具費與設備儀器維修保養費，由本中心檢附單據委請中心助理協助辦理核銷。

- 二、非屬研究計畫、無產學合作計畫契約及產學合作研究成果全數歸屬本校之案件，服務費用應另加計 5%營業稅開立發票。

Article 6 Use of Testing Funds

- I. 20% of the total testing fee is the MCUT management fee, while the other 80% is the Center's consumable fee, stationery fee, and equipment maintenance fee expenses. The Center's assistant will be provided with receipts and will assist in offsetting.
- II. For cases that do not belong to a research project or do not have an industry-university cooperation project contract, or are not part of an industry-university cooperation research project where all the research results belong to the school, the service fee shall be invoiced with an additional 5% business tax.

第七條 試驗結果報告

受委託樣品試驗結果報告以電子檔提供，並以 E-mail 傳送給委託者。

Article 7 Report of Test Results

The report of the test results for the commissioned sample shall be provided in the form of an electronic file and delivered to the client via e-mail.

第八條 附則

- 一、上述規則若未遵守，本中心保留隨時終止、取消、變更儀器使用之權利，以上如有系統操作疑問或特殊情況請洽本中心人員，以免影響個人權利。
- 二、委託單位不得將本單位提供檢測報告用於商業廣告用途。如有商業廣告用途需求者，另依本校「研發成果使用校名(徽)、標誌暨商標管理辦法」規定辦理。

Article 8 Addendum

- I. Where non-compliance with the above-mentioned rules is

identified, the Center retains the right to stop, cancel, and change the use of equipment. Please contact the Center's personnel if there are any questions about system operation or special conditions to avoid affecting your personal rights.

- II. The commissioning party is prohibited from using the testing reports provided by this unit for commercial advertising purposes. For any commercial advertising purposes, please follow the regulations stipulated in our university's "Regulations for the Use of University Name (Emblem), Symbols, and Trademarks on Research and Development Achievements."

第九條 實施與修訂

本辦法經中心事務委員會議通過，校長核定後公佈實施，修訂時亦同。

Article 9 Implementation and Amendment

The Regulations shall be promulgated and implemented after the passage of the Center Council Meeting and the approval of the president. The same shall apply to the amendments hereto.

智慧醫療研究中心儀器設備名稱與學術單位收費標準
Name of Equipment and Academic Institutions Rates of the Research Center for Intelligent Medical Devices

	設備名稱 Name of equipment	分析項目 Analysis item	檢測費用 Rates
1	X 射線繞射光譜儀(XRD) BRUKER, D8 ADVANCE ECO	廣角繞射 Wide-Angle	2,000 元/ 2 小時 NT\$2,000/2hours
		低掠角薄膜繞射 Grazing Incidence	
		高溫模式 High-Temperature Mode	10,000 元/3 小時 NT\$10,000/3 hours (適用量測溫度 1000℃ 以下，註 2)
2	場發射掃描式電子顯微鏡 (FE-SEM) JEOL, JSM-7610F	含以下項目 微結構觀察(SEI) 背向式散射(BEI) 能量分散式光譜儀(EDS)	6,000 元/3 小時 NT\$6,000/3 hours
		波長分散式光譜儀 (WDS)	6,000 元/3 小時 NT\$6,000/3 hours
		鍍白金機 Platinum Coater	500 元/次 NT\$500/time
		截面離子拋光機 Cross-Section Polisher	3,000 元/1 小時 NT\$3,000/1 hour
3	掃描探針顯微鏡 (SPM) BRUKER, MultiMode 8	表面形貌 Surface Topography 力場曲線 Force curve 靜電力顯微模式(EFM) 磁力顯微模式(MFM) 表面電位能顯微模式(KPFM) 導電顯微模式(CAFM) 壓電響應顯微模式(PFM) 掃描電容顯微模式(SCM)	5,000 元/3 小時 探針費用:1,000 元/次 NT\$5,000/3 hours Rate of probe: NT\$1,000/time
4	拉曼光譜儀(Raman) HORIBA, LabRAM HR Evolution	基本光譜量測(RAMAN)	4,000 元/2 小時 NT\$4,000/2hours
		螢光光譜儀(PL)	
		高溫模式 in situ 及 Mapping	
5	X 射線螢光光譜儀(XRF)	元素分析量測定性模式Omnian	4,000 元/2 小時 NT\$4,000/2hours
6	同步熱分析儀(DSC&TGA)	熱示差掃描分析(DSC) 熱重分析(TGA)	2,000 元/2 小時
7	熱膨脹分析儀(DIL)	分析材料相變化溫度/膨脹係數評估	5,000 元/次

註 1：中心成員以收費標準之 1 折計算；校內單位與長庚友校則以收費標準之 7 折計算。RCIMD member are charged 10% of the standard rate. MCUT units and Chang Gung University of Science and Technology are charged 70% of the standard rate.

註 2：X 射線繞射光譜儀(XRD)高溫模式，需加熱至 1000 度以上則需另外評估收費標準。Where the X-Ray Diffraction Spectroscopy (XRD) needs to be heated over 1000°C in the high-temperature mode, the rate shall be individually assessed.

註 3：本收費標準適用於學術單位。This fee schedule is applicable to academic institutions.

智慧醫療研究中心產業界檢測儀器及技術收費標準

Industry Institutions Rates of the Research Center for Intelligent Medical Devices

方案一：

業界以簽約次數收費：以簽約金額 20 萬元起(廠商可依需求往上調整)，計價方式為件數收費之 95 折。

Option I:

The industry charges based on contracts: starting from 200,000 NT dollars (the vendor can adjust upwards according to their needs), with a pricing method of a 5% discount on a per-case basis.

方案二：

業界件數收費。

Option II:

The industry charges based on a per-case.

	設備名稱	分析項目	量測費用
1	白光干涉儀 White Light Interferometry	-每增加一個點分析加收 1000 元 -每增加一個線分析加收 200 元 The analysis fee is increased by 1000 NTD for each additional point and 200 NTD for each additional line.	6000 元/片(含五個點/線) NT\$6,000/Sample(Contains five points/lines) Ex: 每片量測 108 點分析面，每片費用為 6000+103*1000 共為 109000 元整。
2	X 射線繞射光譜儀(XRD)	廣角繞射 Wide-Angle 低掠角薄膜繞射 Grazing Incidence	8,000 元/樣品 NT\$8,000/Sample
		高溫模式(白金載台) High-Temperature Mode	20,000 元/3 小時 NT\$20,000/3hours
3	場發射掃描式電子顯微鏡(FE-SEM)	含以下項目：微結構觀察(SEI)、背向式散射(BEI)、半定量(EDS)	10,000 元/3 小時 NT\$10,000/3hours
		波長分散式光譜儀(WDS)	8,500 元/3 小時 NT\$8,500/3hours
		鍍白金機 Platinum Coater	500 元/次 NT\$500/time
4	掃描探針顯微鏡(SPM)	表面形貌 Surface Topography 單點式/全面式力場曲線 Force curve	8,000 元/3 小時 NT\$8,000/3hours 探針費用:500 元/次 Probe NT\$500/time

		磁力顯微模式 MFM 靜電力顯微模式 EFM 表面電位能顯微模式 SEPM 壓電響應顯微模式 PFM 導電顯微模式 CAFM 掃描電容顯微模式 SCM	10,000 元/3 小時 NT\$10,000/3hours 探針費用:1,000 元/次 Probe NT\$1,000/time
5	同步熱分析儀 Simultaneous Thermal Analysis	1. 熱重分析模式 TGA: 特定溫度條件下樣品的重量變化。 2. 示差掃描熱量分析模式 DSC: 材料熱性質分析 (包含玻璃轉移溫度、熔點、比熱等)。	9,000 元/3 小時 NT\$9,000/3hours 超過 3 小時每小時加收 1,000 元 An additional fee of 1,000 NTD per hour will be charged for each hour exceeding the initial 3 hours.
6	截面離子拋光機 Cross-Section Polisher	利用離子束去切削及拋光樣品表面，可以避免在研磨過程中所產生的應力、拋光液粒子.. 等的殘留。 Using ion beams to cut and polish the surface of the sample.	4,000/1 小時 NT\$4,000/hour
7	硬度測試 Hardness test	1. 材料取樣裁切至適當大小並進行研磨拋光處理。 2. 依客戶需求可執行勃氏、洛氏、維克氏、微維克氏硬度實驗，厚薄板與線材皆可協助。(Brinell、Rockwell、Vickers、Micro Vickers)	3,000/每件 NT\$3,000/Sample
8	金相試片製作與觀察 Metallographic test	1. 金相試片製作包括取樣、鑲埋、研磨、拋光及浸蝕。Metallographic sample preparation involves sampling, embedding, grinding, polishing, and etching. 2. 金相觀察依客戶需求提供所需倍率之金相照片與說明。	8,000/每件 NT\$8,000/Sample
9	破損分析 Failure Analysis	依客戶委託內容討論後報價 Quotation will be provided based on the discussed scope of work as per the client's commission.	論件計費 Charging based on a per-item basis.
10	Reflow test & 色差分析		參考價: (NT\$40,000/爐)x 樣品 Reference price:

			(NT\$40,000 per furnace)x samples.
11	TCT test & 色差分析		參考價: x 月測試時間 x 200,000 元 (高低溫範圍需討論是否可行 Reference price: Testing time in X months x NT\$200,000 (Feasibility of high and low-temperature ranges needs discussion))
12	高溫高濕試驗 Temperature with Humidity		1,500/件 120 小時以內 NT\$1,500/ Sample Within 120 hours
13	熱膨脹分析儀 (DIL)	分析材料相變化溫度/膨脹係數評估 Evaluation of material phase transition temperature/thermal expansion coefficient analysis.	8,000/件 NT\$8,000/Sample
14	X-ray 螢光光譜分析儀(XRF)	用於定量固體和液體樣品元素組成 Used for the quantitative elemental composition analysis of solid and liquid samples.	5,000 元/件 NT\$5,000/Sample
15	拉曼光譜量測 (RAMAN)	應用於分子結構分析與定量化鑑識研究。Applied to molecular structure analysis and quantitative identification research	6,000 元/件 NT\$6,000/Sample 變溫及 Mapping 8,000 元/件 Temperature dependence and mapping NT\$8,000/Sample
16	穿透式電子顯微鏡(TEM)	明-暗視野穿透電子影像、繞射圖像、選區成像、EDS 光譜 Bright-field and dark-field transmitted electron imaging, diffraction imaging, selected area imaging, and EDS spectroscopy.	16,000 元/4 小時 NT\$16,000/4 hours 磨試片費另計 Additional charges for sample preparation.
17	矽膠檢測	DSC 熱示差掃描熱分析儀及 RAMAN 拉曼光譜儀及成分 mapping	25,000 元/件 NT\$25,000/Sample
18	感應耦合電漿放射光譜儀(ICP-OES)	1. 樣品定量分析 Quantitative analysis 2. 試樣定性分析 Qualitative analysis	微波消化前處理: 2000 元/件 Microwave digestion pretreatment: NT\$2,000/Sample 欲測定的元素數目(含檢量線) Number of elements to be determined (including calibration curves): 3 元素以內: 4,500 元/件

			4~6 元素：5,600 元/件 7~10 元素：10,000 元/件 10 元素以上，多一元素： 加 800 元/件 Up to 3 elements: 4,500 NT dollars per sample. 4 to 6 elements: 5,600 NT dollars per sample. 7 to 10 elements: 10,000 NT dollars per sample. For each additional element beyond 10: additional 800 NT dollars per sample.
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備註：其他測試請洽詢中心助理

表號：A0L0030203

明志科技大學智慧醫療研究中心樣品試驗申請單

申請單留存智慧醫療研究中心辦公室

申請單位之系所/公司名稱			申請日期	年 月 日
電子信箱(E-mail)			申請人姓名	
			電話/手機	
申請單位之地址				
收據抬頭			收據統一編號	
儀器設備名稱			檢測項目	
安排樣品分析日期 (本中心填寫)	安排日期	年 月 日 <input type="checkbox"/> 上午 <input type="checkbox"/> 下午	實際日期	年 月 日 <input type="checkbox"/> 上午 <input type="checkbox"/> 下午
樣品數量				
樣品組成元素			樣品性質	
樣品說明	<input type="checkbox"/> 塊材 <input type="checkbox"/> 粉體 <input type="checkbox"/> 薄膜 <input type="checkbox"/> 其他 備註			
實驗目的				
樣品危險性	<input type="checkbox"/> 無毒 <input type="checkbox"/> 有毒: _____			
需求說明	<input type="checkbox"/> 樣品需取回 (請附上回郵郵資、包裝等)	費用	預估:	元(本中心填寫)
			實際:	元(本中心填寫)
委託單位之指導老師/公司主管			委託單位之 研究生/聯絡人	
樣品量測者(本中心填寫)			智慧醫療 中心負責人	

備註：

- 1.請於「樣品組成元素」及「樣品性質」欄位詳述樣品元素及性質，務必誠實申報。如果發現申報不實造成儀器污染或損壞時，本中心有求償的權利。
- 2.請於「檢測項目」欄位詳述樣品需檢測的項目。
- 3.申請內容如有不實，取消使用權利，各項設備申請須在 7 天前提出。
- 4.請將以上表單資料填寫完整後寄本中心貴儀管理者。
- 5.本申請表所蒐集之公司/個人資料，作為試驗分析聯絡之用途，保存兩年於智慧醫療中心辦公室。
- 6.委樣前請先與本中心貴儀管理者聯絡，聯絡資訊:heidwang@mail.mcut.edu.tw 王聖茶小姐

繳款方式	<input type="checkbox"/> 逕至總務處出納組繳款。	繳費日期：
	<input type="checkbox"/> 逕匯入學校帳戶者：請務必於匯款單註明智慧醫療研究中心檢測費及繳款人姓名/單位，入帳後將由智慧醫療研究中心郵寄發票/收據。 請逕匯華南銀行泰山分行 008 專戶存款帳號：193200017296 戶名：財團法人明志科技大學	

表號：A0L0030303

MCUT Research Center for Intelligent Medical Devices Sample Testing Application Form

The application form shall be retained in the Research Center for Intelligent Medical Devices office.

Department/company name of the applicant's unit		Date of application	
E-mail		Name of applicant	
		Phone/mobile	
Address of the applicant's unit			
Payor		Unified business no.	
Name of equipment		Test item	
Scheduled date for sample analysis (for use by the Center only)	Scheduled date	MM / DD / YYYY <input type="checkbox"/> Morning <input type="checkbox"/> Afternoon	Actual date MM / DD / YYYY <input type="checkbox"/> Morning <input type="checkbox"/> Afternoon
Quantity of the sample	_____ items	Composition of the sample	
Description of the sample	<input type="checkbox"/> Bulk material <input type="checkbox"/> Powder <input type="checkbox"/> Film <input type="checkbox"/> Others Note:		
Objective of the experiment			
Dangerousness of the sample	<input type="checkbox"/> Non-toxic <input type="checkbox"/> Toxic: _____		
Description of the requirements	<input type="checkbox"/> Sample should be returned (please deliver the sample with the return postage and packaging)	Fees	Estimated: NT\$ _____ (for use by the Center only)
			Actual: NT\$ _____ (for use by the Center only)
Instructor/officer of the client		Graduate student/contact	
Laboratory equipment technician (for use by the Center only)		Responsible person of RCIMD	

Note: 1. Please describe, in detail, the element and nature of the sample in the "composition of the sample" and "nature of the sample" columns. This must be reported with honesty. Where equipment is contaminated or damaged due to false reporting, the Center has the right to claim compensation.

2. Please describe, in detail, the test items that the sample requires in the "test item" column.
3. Where false content is identified in the application, the right of use shall be canceled. Application for each piece of equipment shall be submitted 7 days before use.
4. Please complete the form above and send it to the assistant of the Center.
5. Personal and company data are collected in this application form for testing, analysis, and contact purposes and will be permanently kept in the Research Center for Intelligent Medical Devices office. This shall be effective immediately.
6. **Please contact the Center's manager of valuable equipment before commissioning the sample. Contact information: Sheng-Fen Wang, heidawang@mail.mcut.edu.tw**

Payment method	<input type="checkbox"/> Paying at the Cashier Section of the Office of General Affairs. <input type="checkbox"/> By remittance to the MCUT account: Please indicate the testing fee to the Research Center for Intelligent Medical Devices and the name/unit of the payor on the remittance advice. The Center shall deliver the receipt by post after we receive the fee. <div style="text-align: right; margin-top: 10px;"> Please transfer to: Hua Nan Bank Taishan Branch 008 Dedicated account: 193200017296 Account name: Ming Chi University of Technology </div>	Date of payment: Receipt No.: